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Synthesis and Study of a Novel 9P-type Mixed Layered Tetradymite-Like GeBi₄Te₄ Compound in the Ge-Te-Bi System

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Taking as a base structural properties of the tetradymite-like layered chalcogenide compounds, a novel ternary GeBi₄Te₄ phase was predicted and synthesized. The polycrystal of this compound was synthesized and its single-crystal was grown by the vertical Brigman-Stokbarger method. The phase composition of obtained samples was analyzed by differential thermal analysis (DTA), X-ray powder diffraction (XRD), and scanning electron microscope (SEM). It was determined that the novel phase melts peritectically at 538 °C and has the following lattice parameter values in a hexagonal configuration: $a = 4.4071(6)$ Å, $c = 17.384(2)$ Å (sp. gr P3m1). This crystal structure is considered a derivative of tetradymite-like layered chalcogenides and consists of alternating Bi bilayers and GeBi₂Te₄ septuple packets.

Key words: Ge-Bi-Te ternary system, new ternary compound, GeBi₄Te₄, tetradymite-like structure, Bi-bilayers, topological insulators.

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Introduction

Chalcogenides are used as a main constituent in the design of such materials like solar panels, infrared detectors, new-generation refrigerators, semiconductors, thermoelectric materials etc. [1-4]. One of the contemporary methods in seeking new functional materials is preparation of phases with more complex and long-period mixed layered structures. Ternary compounds of the homologous series $(A^{IV}Te)_n(B_2^VTe_3)_m$ ($A^{IV} = Ge, Sn, Pb$; $B^V = Sb, Bi$) are long studied thermoelectric materials [5-12]. The thermal conductivity of such alloys possessing a large unit cell and heavy element atoms, is reduced due to the effective scattering of phonons, that causes to the increase of the thermoelectric effect. Last investigations demonstrated that these materials carry topological insulator properties and have wide potential application in optoelectronics, spintronics, and quantum computing [13-24].

In this context, interest to the study of the $nGeTe \cdot mBi_2Te_3$ ($n = 1 - 9$, $m = 1 - 4$) homologous series has been significantly increased. GeTe-rich ($(n/m) \geq 1$) and Bi₂Te₃-rich ($(n/m) < 1$) compounds substantially differ from each

other due to their structures [25-28]. Inclusion of the GeTe to the five-layer Bi₂Te₃ slab yields the seven-layered GeBi₂Te₄ packet with R-3m space group and congruent melting at 585 °C. Subsequent additions of GeTe bilayers increase the number of layers by two. As a result, the structure of Ge₂Bi₂Te₅, Ge₃Bi₂Te₆, and Ge₄Bi₂Te₇ [29] compounds consist of packages that are stacked along the c axis in 9, 11, and 13 layers respectively. Bi₂Te₃-rich ($(n/m) < 1$) alloys demonstrate mixed-layered structures. Their crystal structure consists of two types of slabs: a five-layered tetradymite packet and a seven-layered GeBi₂Te₄ packet. GeBi₄Te₇ and GeBi₆Te₁₀ compounds consist of five and seven-layered packets that are stacked in an ordered sequence and bonded with each other by the Van der Waals bonds. The general formula of the Bi₂Te₃-rich mixed-layered compounds can be represented as $nGeBi_2Te_4 \cdot mBi_2Te_3$.

Literature data shows that in addition to the substitution of seven- and five-layered packets, there is extensive information about the existence of $nB_2^V \cdot mB_2^V X_3$ homologous series [30-33]. Their structure research suggests that the crystal structure of these compounds consists of five-layered $mB_2^V X_3$ and two-layered nB_2^V

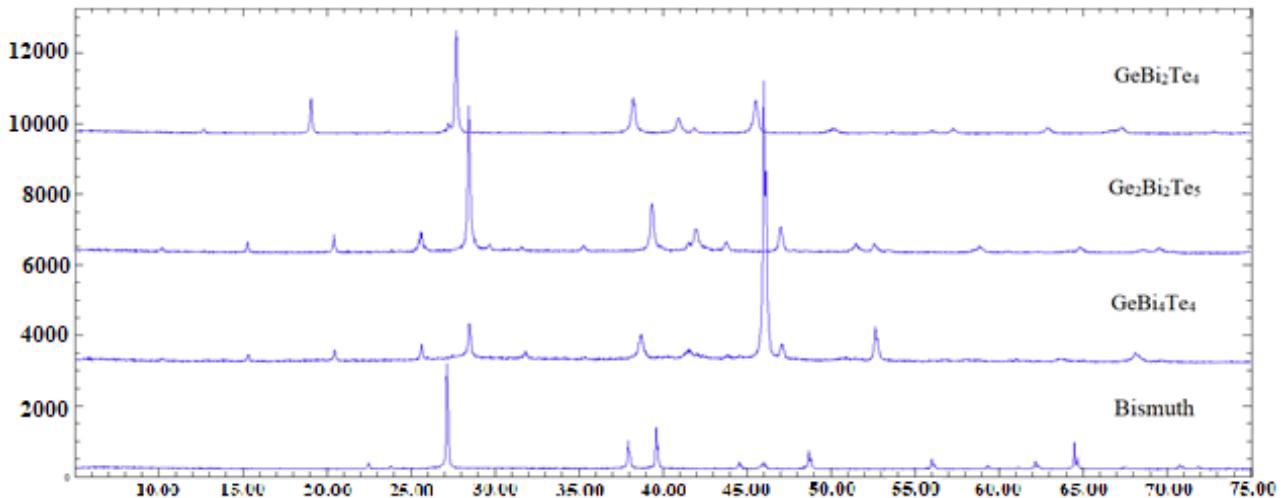


Fig. 1 . PXRD patterns of bismuth, GeBi_2Te_4 , $\text{Ge}_2\text{Bi}_2\text{Te}_5$, and GeBi_4Te_4 .

packets that are stacked along the c axis in an ordered manner.

Data analysis indicates that in A^{IV} - B^V - Te systems, besides above mentioned homologous series, there can also exist phases relevant to $m\text{Bi}_2$ - $A^{IV}B_2^V\text{Te}_4$ homologous series. The first two members of this series have been reported in recent years: SnBi_4Te_4 [34] and GeSb_4Te_4 [35]. Identification of these compounds increases the probability of such phases in a similar Ge - Bi - Te system. Taking into account mentioned facts in the presented paper, a new mixed layered phase consisting of the repetition of seven-layered GeBi_2Te_4 and two-layered Bi packets was synthesized and investigated.

I. Experimental part

High purity Ge (99.999 %, Alfa Aesar), Bi (99.999 %, Alfa Aesar), and Te (99.999 %, Alfa Aesar) elements were used to synthesize the GeBi_4Te_4 polycrystalline sample and to prepare its single-crystalline ingot. According to stoichiometric amounts, 1 g of sample was sealed under the vacuum (10^{-2} Pa) in quartz ampoule and heated up to 800 °C, and kept at this temperature for 3 h. For better dissolving, the sample was mixed by shaking. The synthesized alloy was quenched in ice water and further annealed at 450 °C for 1000 h in order to reach the equilibrium state. Additionally, single-crystal with starting composition of GeBi_4Te_4 was grown from the melt using the vertical Brigman-Stockbarger method. Initially, conical-bottom quartz ampoule was filled with 8 g of the stoichiometric mixture and sealed under the vacuum (10^{-2} Pa). This ampoule was kept in the hot zone (630 °C) of the two-zone furnace for 3 h to ensure that the sample was completely liquefied. Then, the ampoule was descended at the rate of 1 mm/h from the hot zone to the cold zone (430 °C). The obtained ingots were studied using DTA, PXRD, and SEM methods.

“NETZSCH 404 F1 Pegasus” system was used for differential thermal analysis. Powder X-ray phase analysis was performed at room temperature in the range of $2\theta = 5$ - 75 degrees with Bruker D2 PHASER X-ray diffractometer ($\text{CuK}_{\alpha 1}$ radiation). Lattice parameters were

calculated with the help of TOPAS V3.0 software. SEM analysis was determined by the HITACHI SU8030 system.

II. Results and discussion

The powder XRD pattern of the obtained polycrystalline sample GeBi_4Te_4 is compared with bismuth, GeBi_2Te_4 , and $\text{Ge}_2\text{Bi}_2\text{Te}_5$ (Fig. 1). Comparison of the diffraction data shows that, there are new diffraction lines in the diffraction pattern of the synthesized GeBi_4Te_4 sample that are not typical for bismuth and GeBi_2Te_4 . The XRD result of the new phase was indexed with the help of TOPAS V3.0 software and it was identified to be a 9P-type GeBi_4Te_4 compound with tetradymite-like layered structure.

It should be noted that, composition of the 9P- GeBi_4Te_4 ($a = 4.40$ Å, $c = 17.38$ Å) and 9P- $\text{Ge}_2\text{Bi}_2\text{Te}_5$ ($a = 4.29$ Å, $c = 17.35$ Å) compounds are different, however both of them consist of a nine-layer packages. For this reason, c parameter in their crystal structures is very close to each other. This causes the diffraction peaks to overlap at lower angles.

A single-crystalline ingot of the synthesized phase was used for XRD, DTA and SEM measurements. It is clearly seen that diffraction patterns of both samples are identical (Fig. 2).

The heating thermogramme of the GeBi_4Te_4 phase is given in Figure 3. As can be seen from the figure, it contains three endothermic effects. The first endothermic effect observed at 538 °C refers to the peritectic decomposition of the GeBi_4Te_4 compound. We assume that the second endothermic effect (at 563 °C) belongs to the decomposition of the Ge-rich phase in the $m\text{Bi}_2$ - GeBi_2Te_4 homologous serie. For accurate results, additional studies are needed. Finally, the endothermic effect at 580 °C indicates the end of the melting process.

SEM and microstructure images of the GeBi_4Te_4 compound are given in Figure 4. It is obvious from the

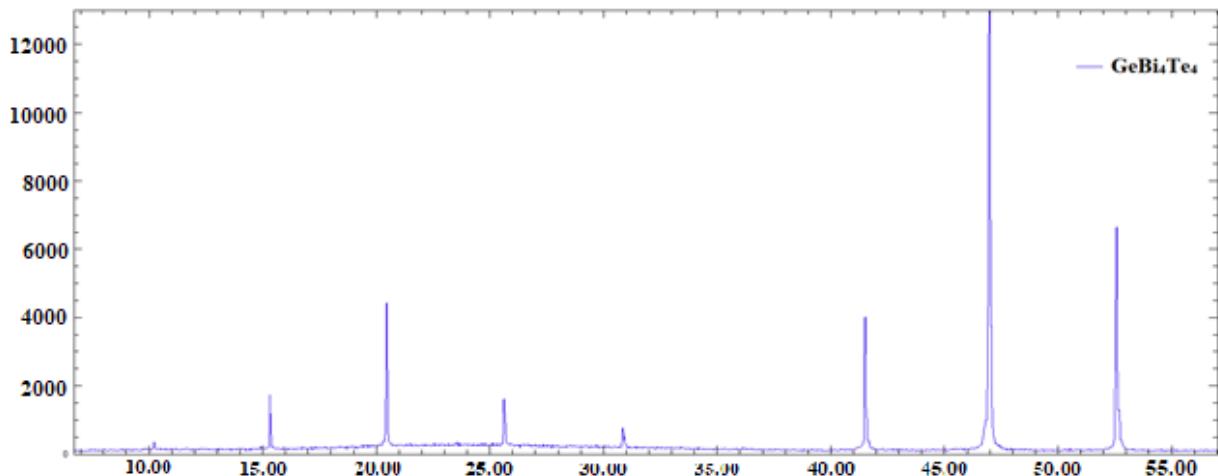


Fig. 2. XRD pattern of a sample from a surface of the GeBi_4Te_4 single-crystal ingot.

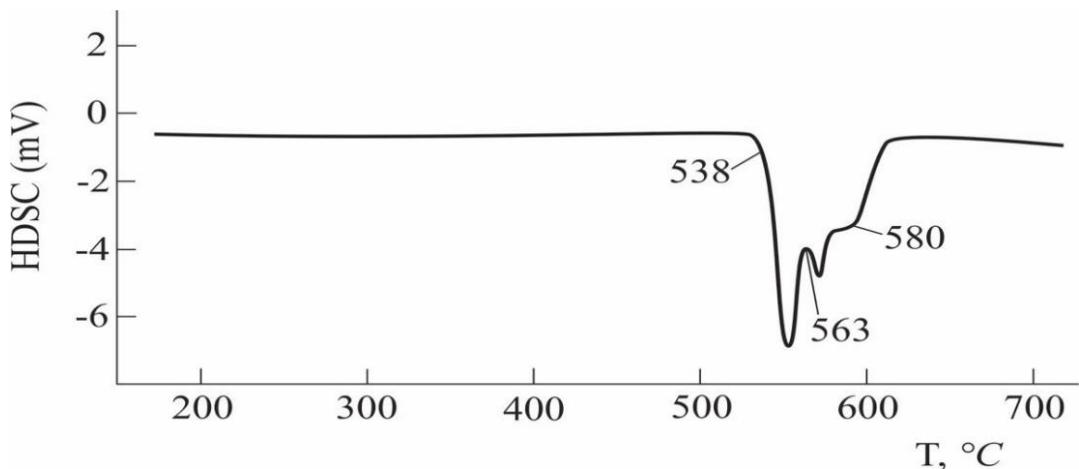


Fig. 3. DTA heating thermogramme of the GeBi_4Te_4 phase.

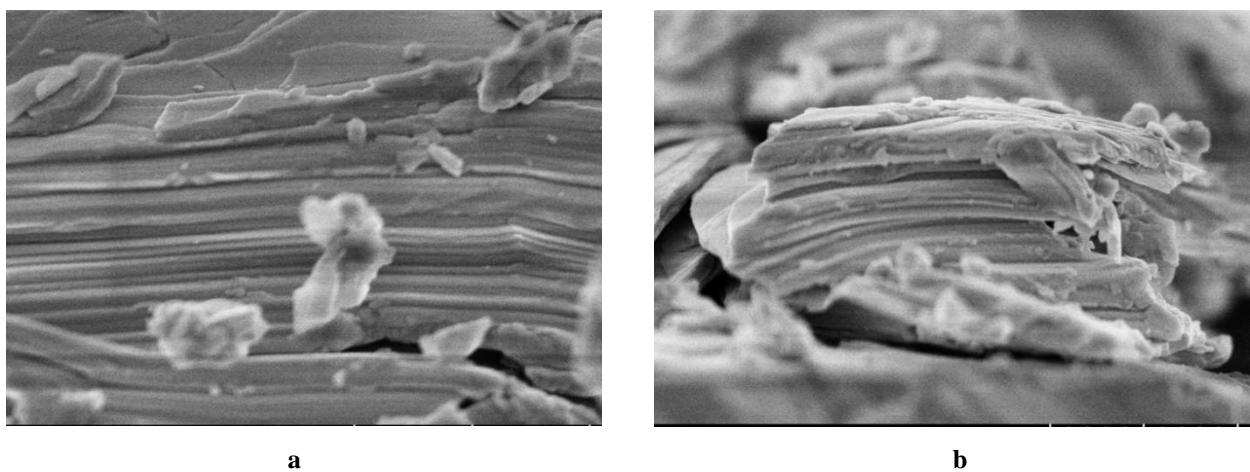


Fig. 4. SEM images of the GeBi_4Te_4 phase.

image that the compound has a mixed layered structure. The EDS balance is very close to the stoichiometric composition of GeBi_4Te_4 .

The crystal structure of GeBi_4Te_4 is given in Figure 5.

The structure of GeBi_4Te_4 can be described as an ordered stacking sequence of Bi bilayers and rocksalt-type GeBi_2Te_4 blocks which are connected by the Van der Waals bonds.

Conclusion

A novel 9P-type tetradyomite-like mixed layered GeBi_4Te_4 compound was synthesized and identified in Ge-Te-Bi ternary system. This compound melts incongruently at 538 °C and crystallizes in the hexagonal lattice: $a = 4.4071(6)$ Å, $c = 17.384(2)$ Å (sp. gr P3m1). This phase consists of alternating Bi bilayers and GeBi_2Te_4 septuple packets. Existence of this type compound in Ge-Te-Bi ternary system increases the probability of similar complex structural phases in $m\text{Bi}_2 - A^{IV}B^V\text{Te}_4$ homologous series. Obtained novel compound tempts attention as potential topological insulators.

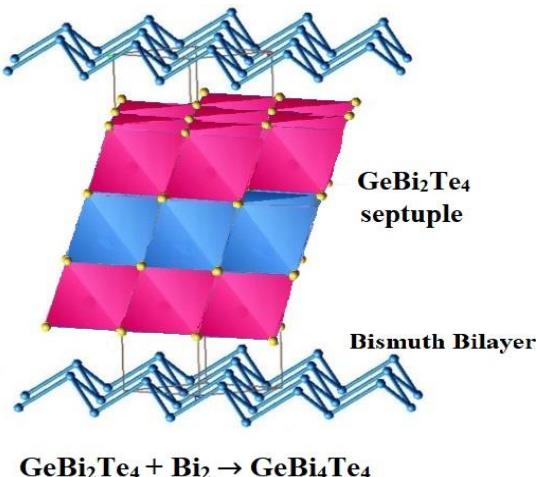


Fig. 5. Crytal strucuture of GeBi_4Te_4 .

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Синтез та дослідження нової змішаної шаруватої 9Р-типу тетрадимітоподібної сполуки GeBi₄Te₄ у системі Ge-Te-Bi

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Взявши за основу структурні властивості тетрадимітоподібних шаруватих халькогенідних сполук, було передбачено та синтезовано нову потрійну фазу GeBi₄Te₄. Синтезовано полікристалічну сполуку, а монокристал вирощено вертикальним методом Бриджмена-Стокбаргера. Фазовий склад отриманих зразків аналізували за допомогою диференціального термічного аналізу (DTA), X-променевої порошкової дифракції (XRD) та скануючого електронного мікроскопа (SEM). Встановлено, що нова фаза перитоційно плавиться при 538°C і володіє наступними значеннями параметрів гратки в гексагональній конфігурації: $a = 4,4071(6)$ Å, $c = 17,384(2)$ Å (sp. Gr P3m1). Така кристалічна структура вважається похідною тетрадимітоподібних шаруватих халькогенідів і складається із змінних бішарів Bi та септуплетних пакетів GeBi₂Te₄.

Ключові слова: потрійна система Ge-Bi-Te, нова потрійна сполука, GeBi₄Te₄, тетрадимітоподібна структура, шари Bi, топологічні ізолятори.